


Search Notes 	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/659,101	CHAN ET AL.	
	Examiner	Art Unit	
	Randall Chin	1744	

SEARCHED			
Class	Subclass	Date	Examiner
15	143.1	↓	↓
15	167.1	8/1/2005	RC
15	22.1	↓	↓
UPDATED SEARCH		3/5/06	RC
D4	138	↓	↓
UPDATED SEARCH		7/5/06	RC

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
Inventor name search	8/1/2005	RC